



AVTECH ELECTROSYSTEMS LTD.

NANOSECOND WAVEFORM ELECTRONICS
SINCE 1975

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PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B
Type: Semiconductor Device Tester
S.N.: 12420
Date: April 21, 2010

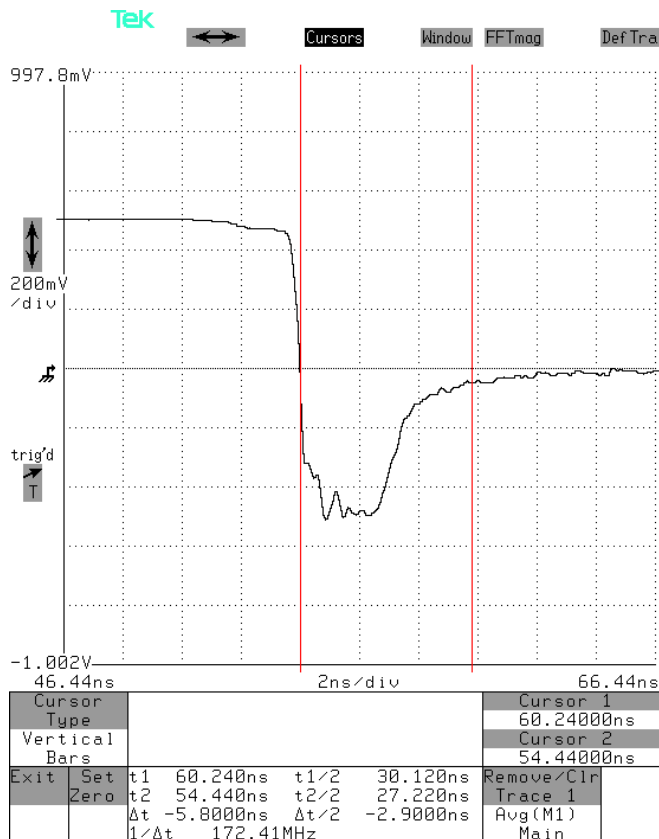
Output Amplitude: to +100 mA, -100 mA
Pulse Width (FWHM): 200 ns
Switching Time,
+ to -, 10%-90%: ≤ 300 ps (at mainframe)
PRF: 1 - 10 kHz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

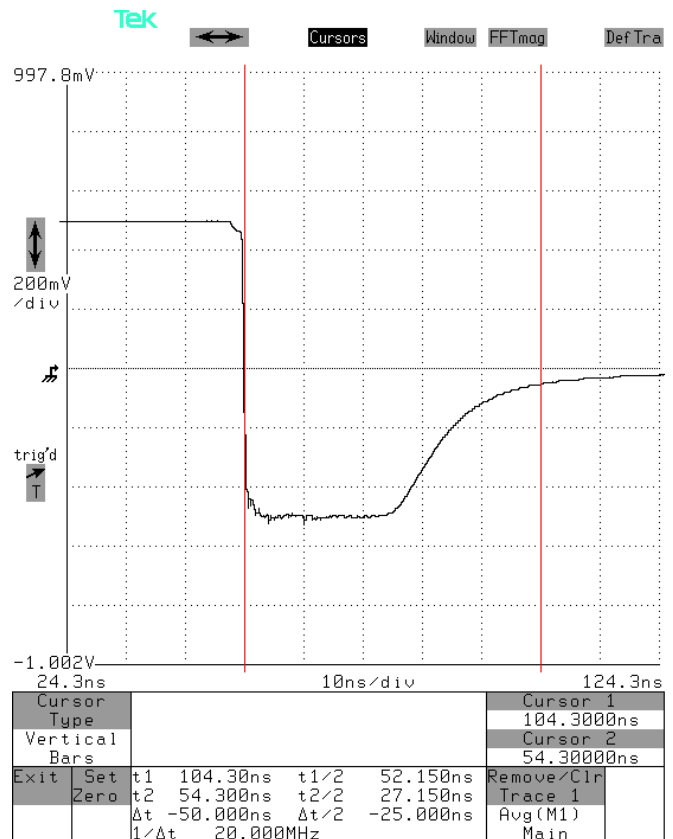
With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:



$I_F = +100 \text{ mA}$, $I_R = -100 \text{ mA}$

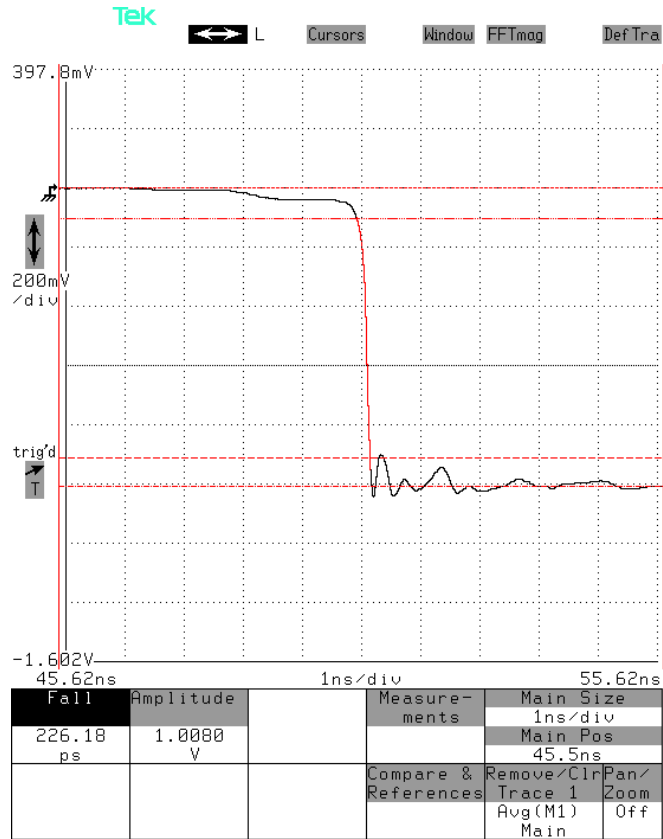
Measured $t_{RR} = 5.8 \text{ ns}$.



$I_F = +100 \text{ mA}$, $I_R = -100 \text{ mA}$

Measured $t_{RR} = 50 \text{ ns}$.

Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 2 ns/div):



Shows a 10%-90% transition time of 226 ps.

For more sample waveforms, please see the "Typical Results" section of the manual.